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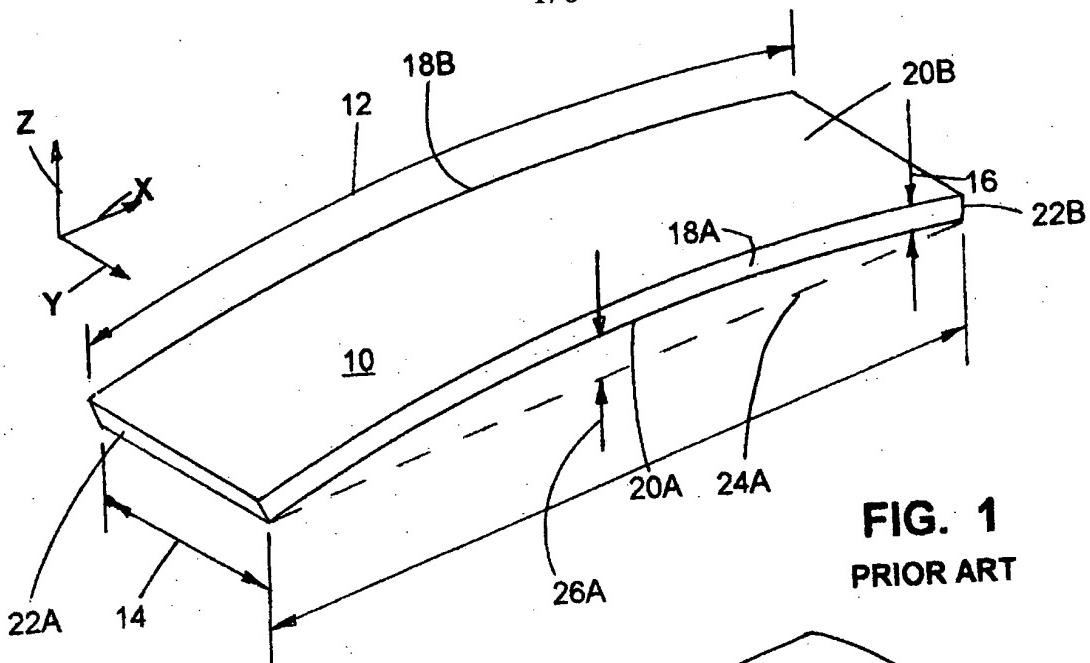


FIG. 1
PRIORITY ART

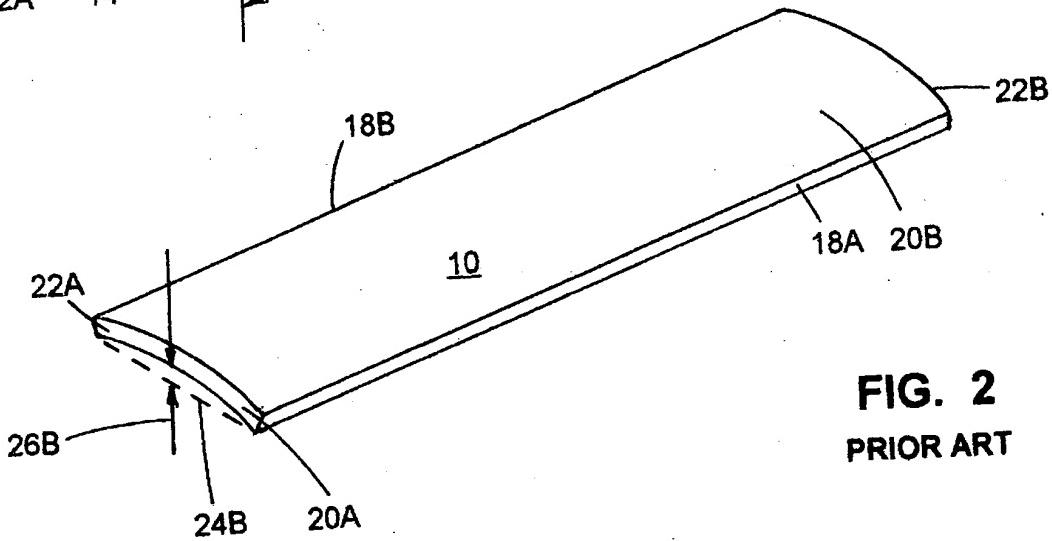


FIG. 2
PRIORITY ART

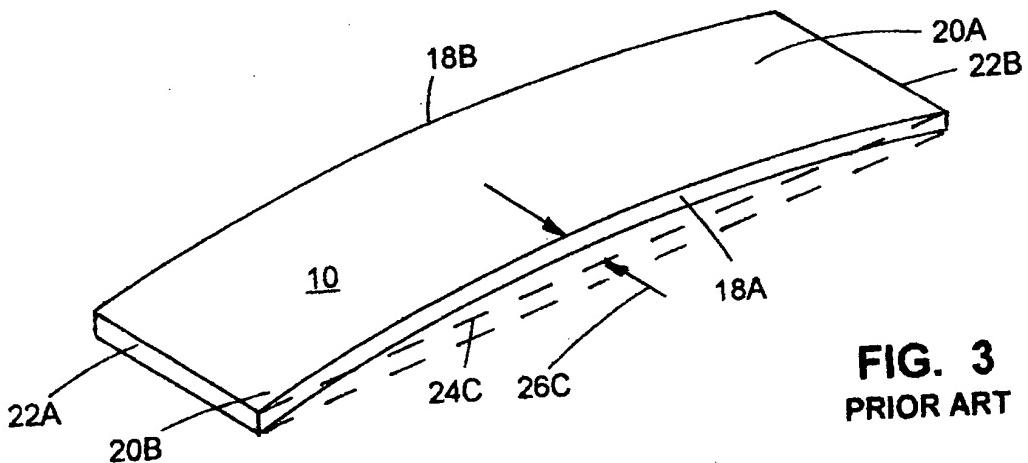


FIG. 3
PRIORITY ART

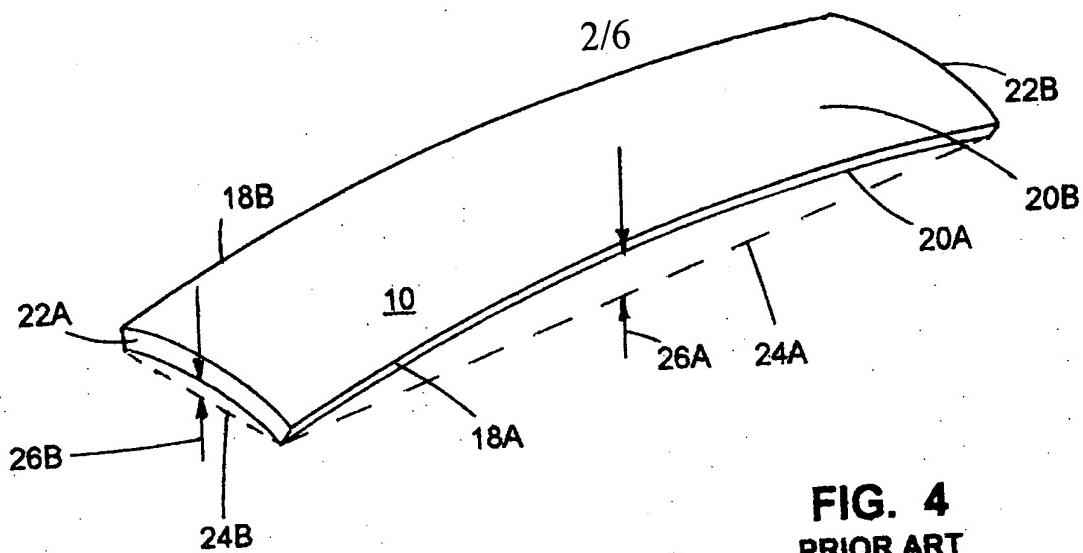


FIG. 4
PRIORITY ART

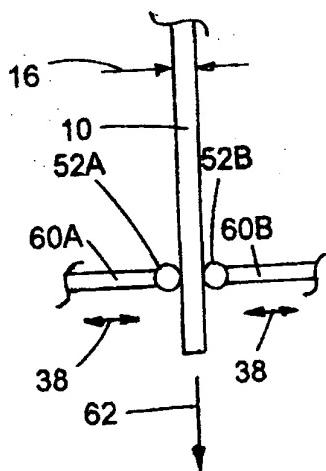


FIG. 6

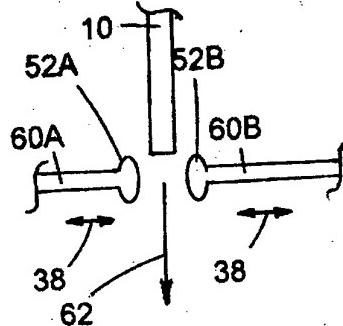


FIG. 7

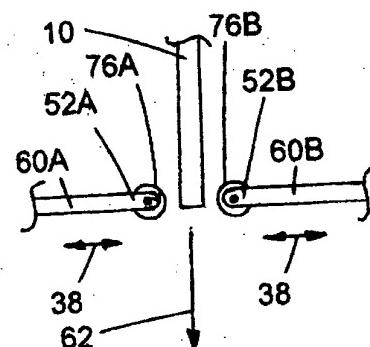


FIG. 8

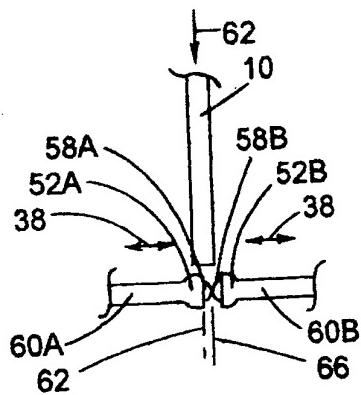


FIG. 9

TITLE: METHOD AND APPARATUS FOR MEASUREMENT OF
THICKNESS AND WARPAGE OF SUBSTRATES

Inventor: Rodney L. Kirstine
Serial No.: Not Yet Assigned
Docket No.: 2269-5659US

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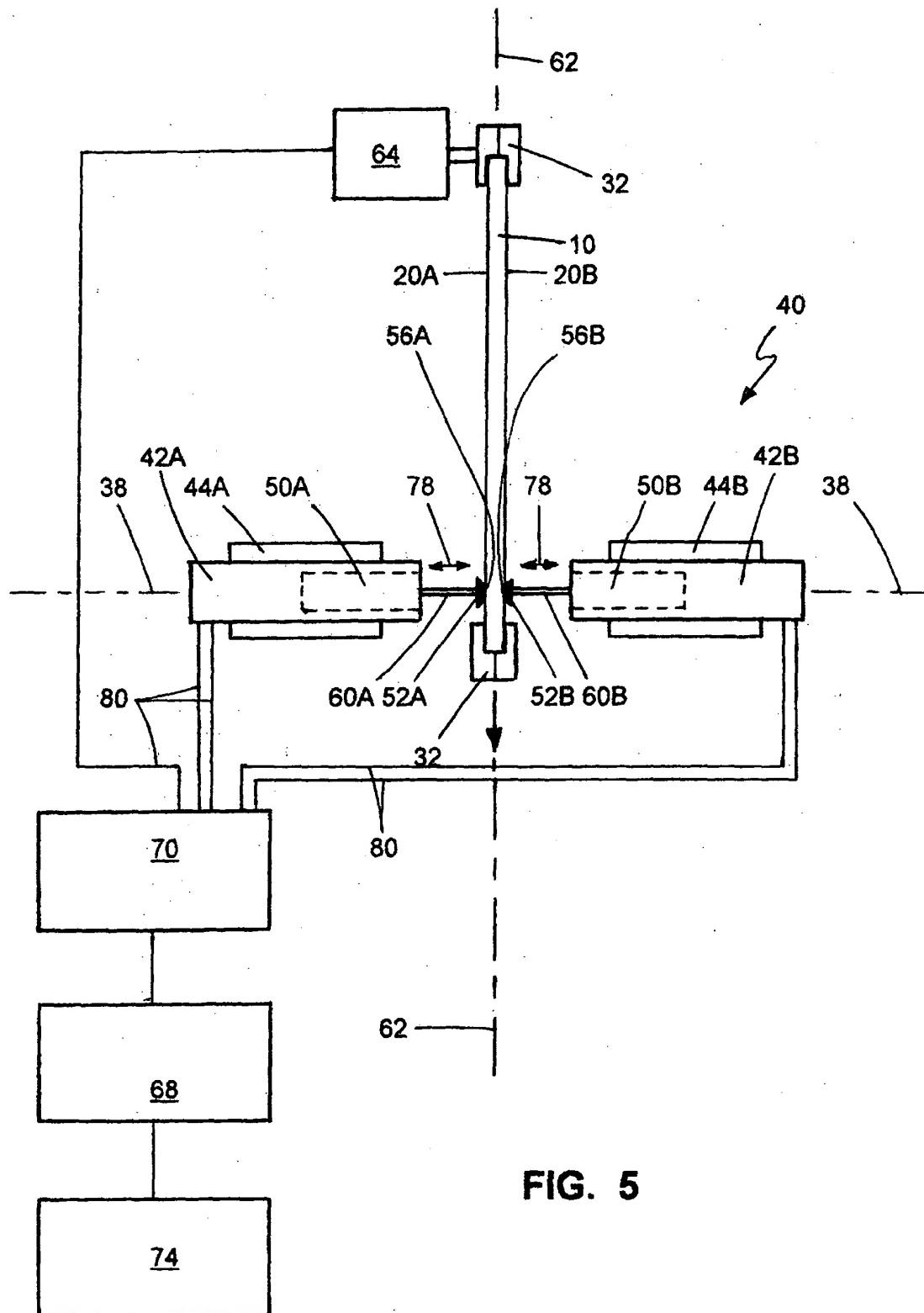


FIG. 5

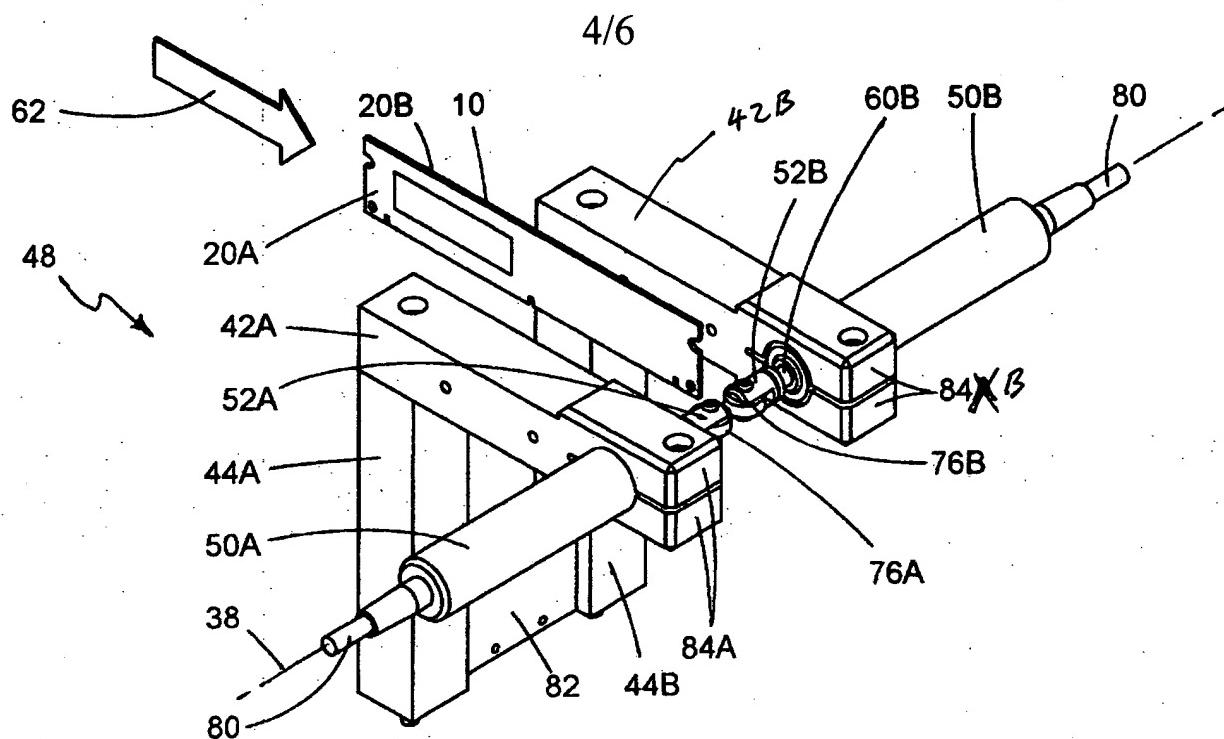


FIG. 10

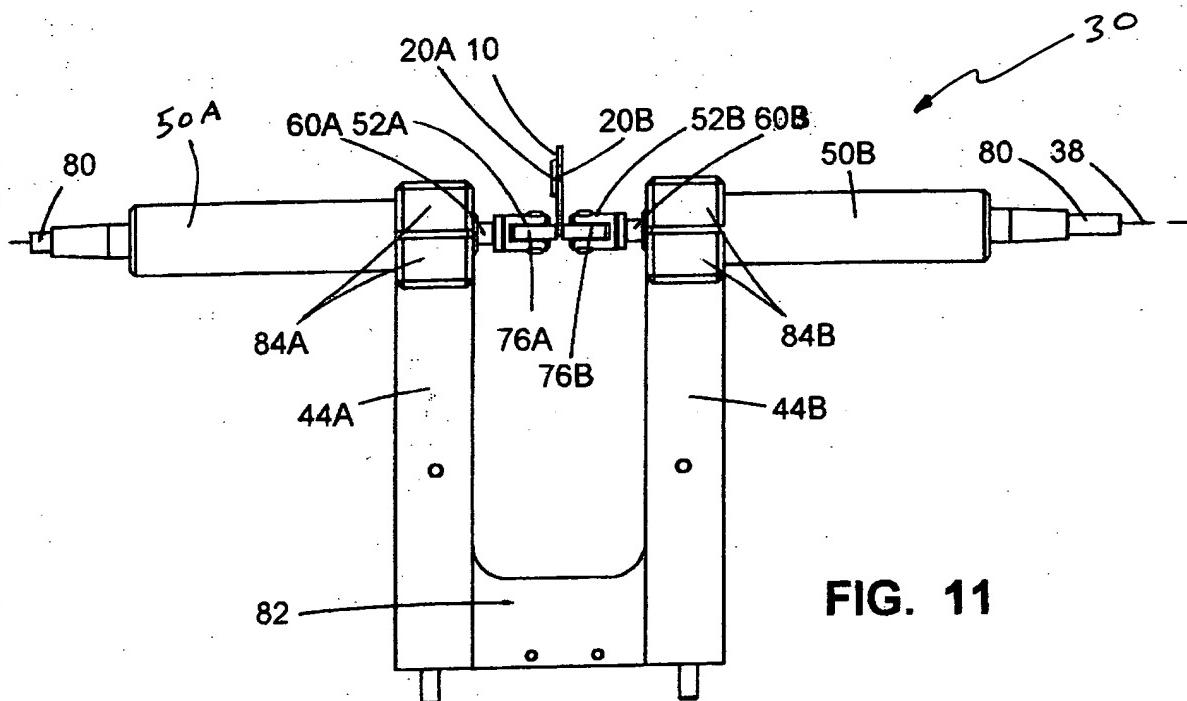


FIG. 11

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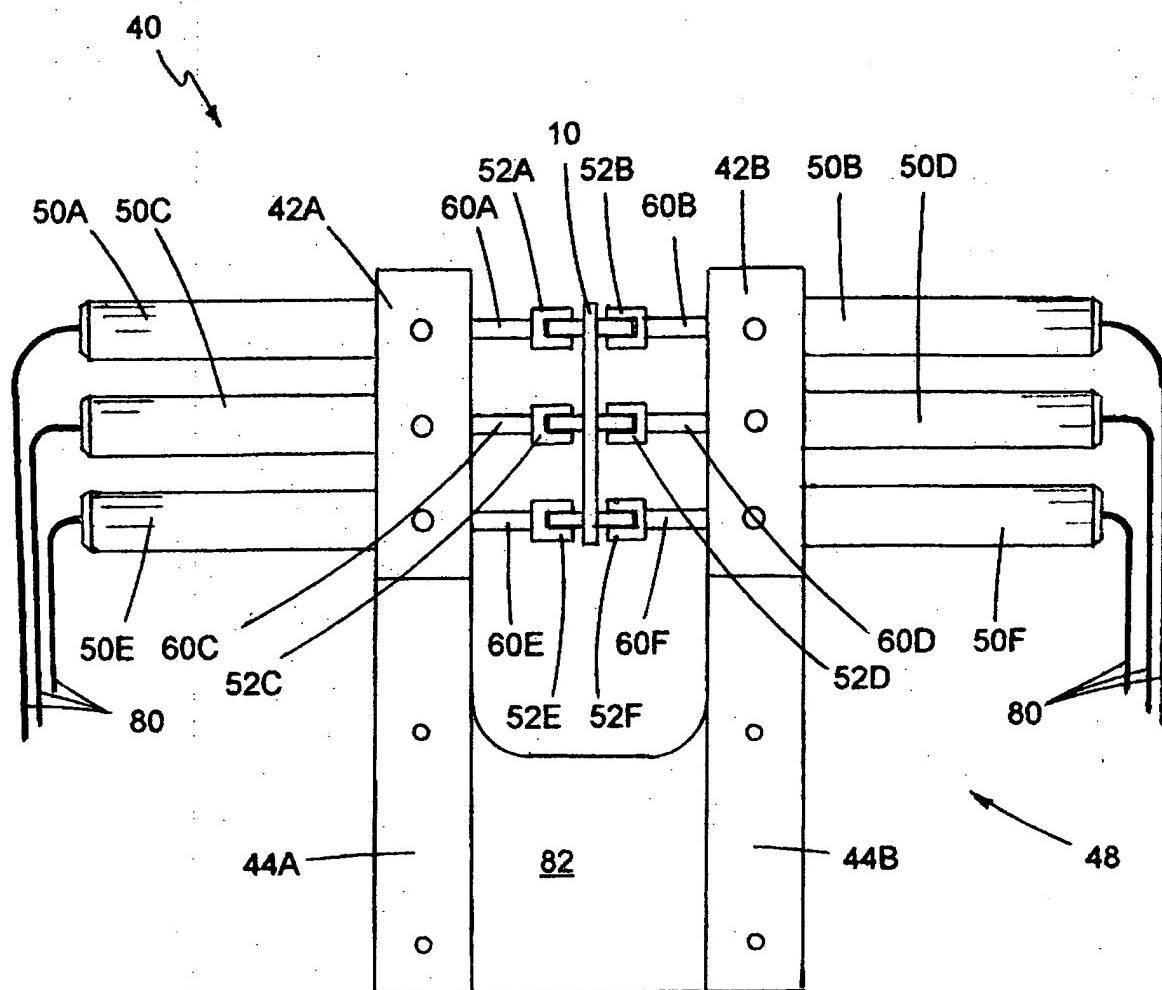


FIG. 12

ATTEL METHOD AND APPARATUS FOR MEASUREMENT OF
THICKNESS AND WARPAGE OF SUBSTRATES

Inventor: Rodney L. Kirstine
Serial No.: Not Yet Assigned
Docket No.: 2269-5659US

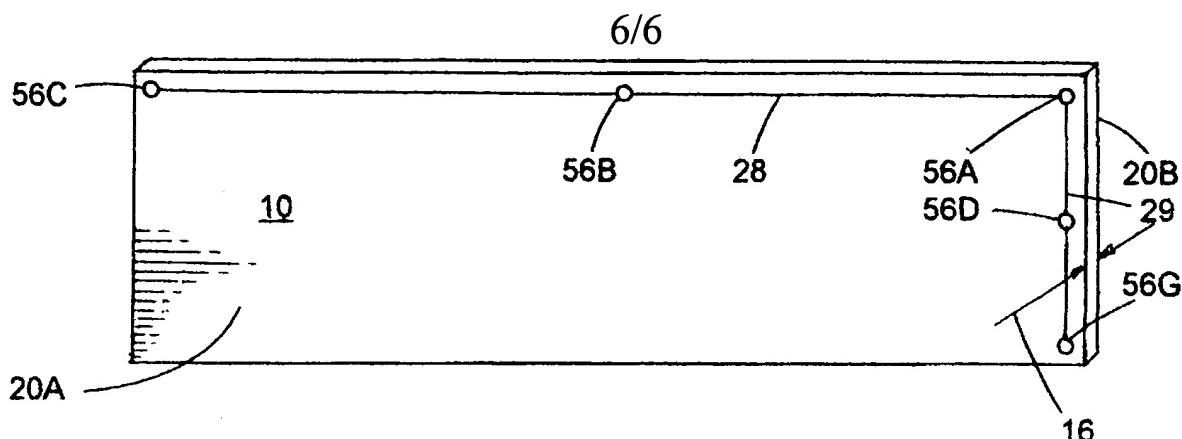


FIG. 13

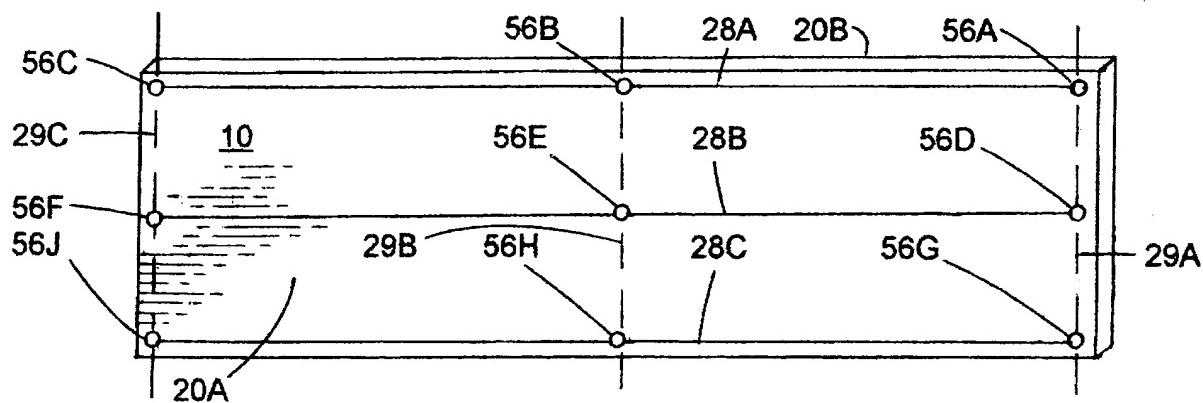


FIG. 14

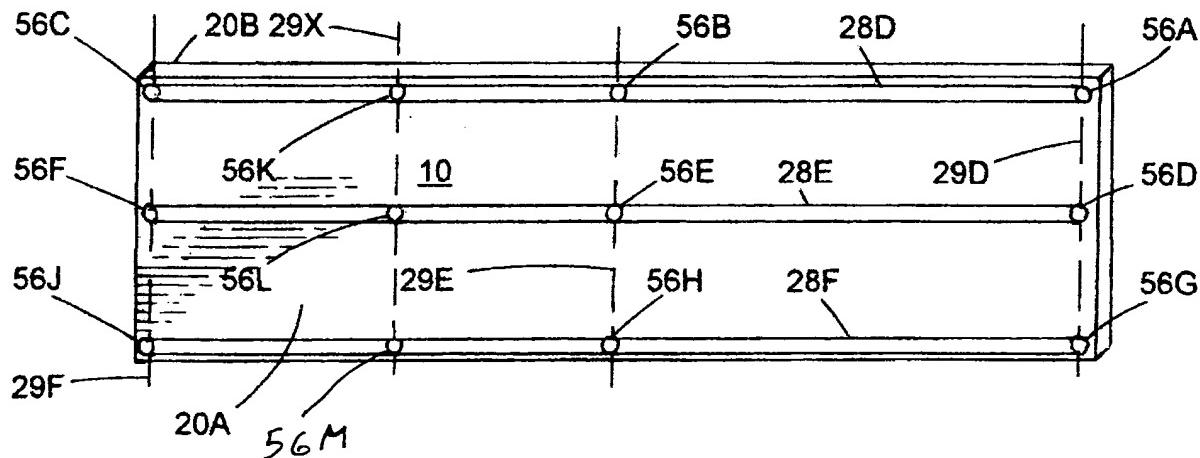


FIG. 15